Power MOSFET

30 V, 7.4 m Ω , 47 A, Single N–Channel, µ8FL

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- NVTFS4C10NWF Wettable Flanks Product
- NVT Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

MAXIMUM RATINGS ($T_J = 25^{\circ}C$ unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V _{DSS}	30	V
Gate-to-Source Voltage			V_{GS}	±20	V
Continuous Drain		T _A = 25°C	I _D	15.3	Α
Current R _{θJA} (Notes 1, 2, 4)		T _A = 100°C		10.8	
Power Dissipation R _{θJA}		T _A = 25°C	P _D	3.0	W
(Notes 1, 2, 4)	Steady	T _A = 100°C		1.5	
Continuous Drain	State	T _C = 25°C	I _D	47	Α
Current $R_{\psi JC}$ (Notes 1, 3, 4)		T _C = 100°C		33	
Power Dissipation		T _C = 25°C	P_{D}	28	W
$R_{\psi JC}$ (Notes 1, 3, 4)		T _C = 100°C		14	W
Pulsed Drain Current	$T_A = 25^{\circ}$	C, t _p = 10 μs	I _{DM}	196	Α
Operating Junction and Storage Temperature			T _J , T _{stg}	–55 to +175	°C
Source Current (Body Diode)			IS	53	Α
Single Pulse Drain-to-Source Avalanche Energy $(T_J = 25^{\circ}C, V_{GS} = 10 \text{ V}, I_L = 10.2 \text{ A}, L = 0.5 \text{ mH})$			E _{AS}	26	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain) (Notes 1, 3)	$R_{\psi JC}$	5.4	
Junction–to–Ambient – Steady State (Notes 1, 2)	$R_{\theta JA}$	50	°C/W

- The entire application environment impacts the thermal resistance values shown; they are not constants and are valid for the specific conditions noted.
- 2. Surface-mounted on FR4 board using 650 mm², 2 oz. Cu Pad.
- Assumes heat-sink sufficiently large to maintain constant case temperature independent of device power.
- 4. Continuous DC current rating. Maximum current for pulses as long as one second is higher but dependent on pulse duration and duty cycle.

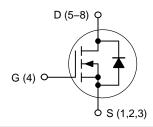


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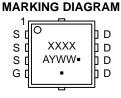
V _{(BR)DSS}	R _{DS(on)} MAX	I _D MAX	
30 V	7.4 m Ω @ 10 V	47 A	
	11 mΩ @ 4.5 V	47 A	

N-Channel MOSFET





WDFN8 (μ8FL) CASE 511AB



4C10 = Specific Device Code for

NVMTS4C10N

10WF = Specific Device Code of

NVTFS4C10NWF

A = Assembly Location

Y = Year

WW = Work Week

= Pb–Free Package

(Note: Microdot may be in either location) ORDERING INFORMATION

See detailed ordering and shipping information on page 5 of this data sheet.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit	
OFF CHARACTERISTICS						•		
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V	
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} / T _J				14.5		mV/°C	
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V, V _{DS} = 24 V	$T_{J} = 25^{\circ}C$ $T_{J} = 125^{\circ}C$			1.0	μΑ	
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS}				±100	nA	
ON CHARACTERISTICS (Note 5)	•						<u> </u>	
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_{D}$	= 250 μΑ	1.3		2.2	V	
Threshold Temperature Coefficient	V _{GS(TH)} /T _J	00 2012	· · · · · · · · · · · · · · · · · · ·		-4.5		mV/°C	
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 30 A		5.9	7.4		
		V _{GS} = 4.5 V	I _D = 15 A		8.8	11	mΩ	
Forward Transconductance	9 _{FS}	V _{DS} = 1.5 V, I	_D = 15 A		43		S	
Gate Resistance	R _G	$T_A = 25^{\circ}$			1.0		Ω	
CHARGES AND CAPACITANCES				1	<u>I</u>	1	1	
Input Capacitance	C _{ISS}				993			
Output Capacitance	C _{OSS}	V _{GS} = 0 V, f = 1 MH	V _{GS} = 0 V, f = 1 MHz, V _{DS} = 15 V		574		pF	
Reverse Transfer Capacitance	C _{RSS}		, 50		163		1	
Capacitance Ratio	C _{RSS} /C _{ISS}	V _{GS} = 0 V, V _{DS} = 15 V, f = 1 MHz			0.164			
Total Gate Charge	Q _{G(TOT)}	00 1 20			10.1		nC	
Threshold Gate Charge	Q _{G(TH)}				1.8			
Gate-to-Source Charge	Q _{GS}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 100 \text{ V}$	15 V; I _D = 30 A		2.6			
Gate-to-Drain Charge	Q_{GD}				6.1			
Gate Plateau Voltage	V _{GP}				3.2		V	
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 1	15 V; I _D = 30 A		19.3		nC	
SWITCHING CHARACTERISTICS (Note 6								
Turn-On Delay Time	t _{d(ON)}				9.0			
Rise Time	t _r	Voc = 45 V Vo	o = 15 V		30		ns	
Turn-Off Delay Time	t _{d(OFF)}	$V_{GS} = 4.5 \text{ V}, V_{D}$ $I_{D} = 15 \text{ A}, R_{G}$	$= 3.0 \Omega$		14			
Fall Time	t _f				7.0			
Turn-On Delay Time	t _{d(ON)}	$V_{GS} = 10 \text{ V}, V_{DS} = 15 \text{ V},$ $I_{D} = 15 \text{ A}, R_{G} = 3.0 \Omega$			6.0			
Rise Time	t _r				25		ns	
Turn-Off Delay Time	t _{d(OFF)}				18			
Fall Time	t _f				4.0			
DRAIN-SOURCE DIODE CHARACTERIS	TICS						<u> </u>	
Forward Diode Voltage	V_{SD}	V _{GS} = 0 V,	T _J = 25°C		0.80	1.1	V	
		$I_{S} = 10 \text{ A}$	T _J = 125°C		0.67			
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V, dIS/dt} = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 30 \text{ A}$			23.3			
Charge Time	ta				12.7		ns	
Discharge Time	t _b				10.6	<u> </u>		
Reverse Recovery Charge	Q _{RR}				8.3		nC	

^{5.} Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS

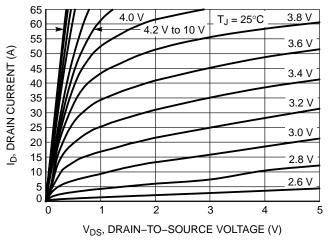


Figure 1. On-Region Characteristics

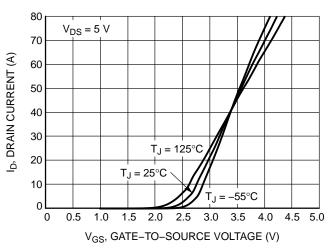


Figure 2. Transfer Characteristics

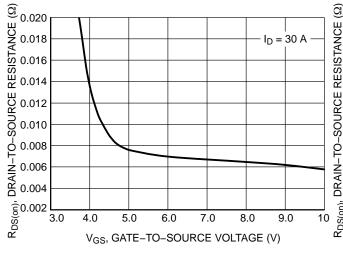


Figure 3. On-Resistance vs. V_{GS}

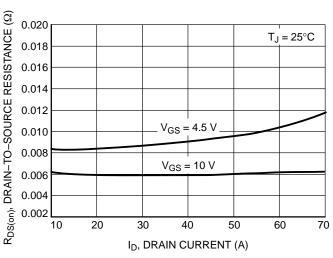


Figure 4. On–Resistance vs. Drain Current and Gate Voltage

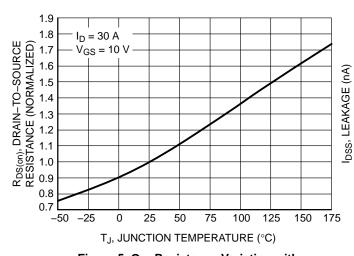


Figure 5. On–Resistance Variation with Temperature

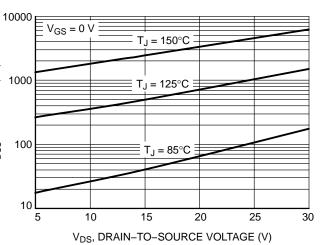


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

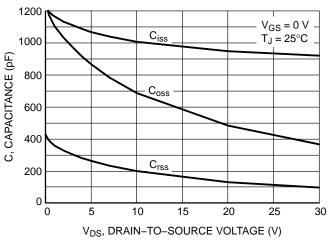


Figure 7. Capacitance Variation

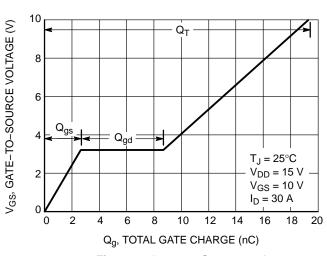


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

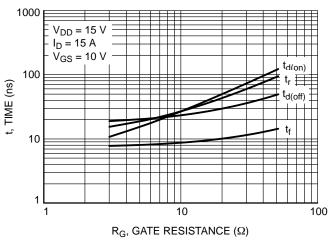


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

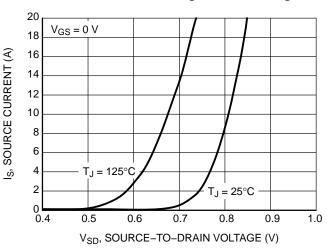


Figure 10. Diode Forward Voltage vs. Current

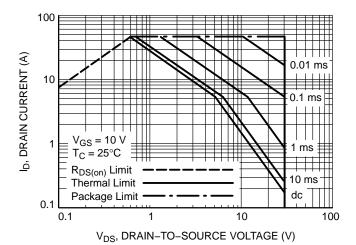


Figure 11. Maximum Rated Forward Biased Safe Operating Area

TYPICAL CHARACTERISTICS

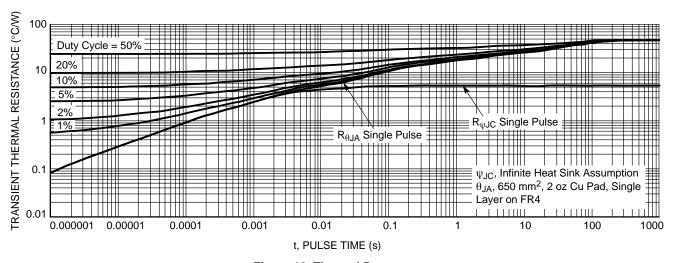
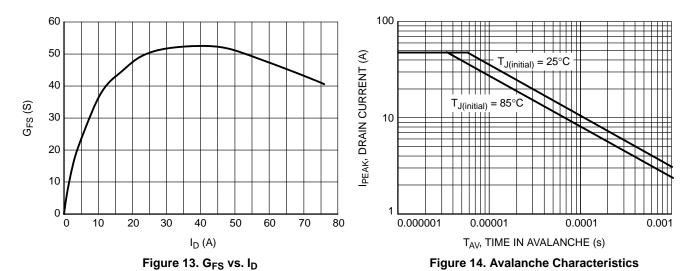


Figure 12. Thermal Response



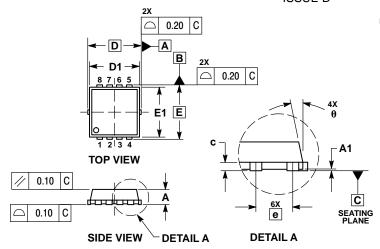
ORDERING INFORMATION

Device	Package	Shipping [†]		
NVTFS4C10NTAG	WDFN8 (Pb-Free)	1500 / Tape & Reel		
NVTFS4C10NWFTAG	WDFN8 (Pb-Free)	1500 / Tape & Reel		

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

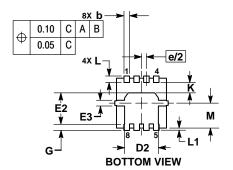
PACKAGE DIMENSIONS

WDFN8 3.3x3.3, 0.65P CASE 511AB ISSUE D



- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- CONTROLLING DIMENSION: MILLIMETERS.
 DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

	MILLIMETERS			INCHES			
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.70	0.75	0.80	0.028	0.030	0.031	
A1	0.00		0.05	0.000		0.002	
b	0.23	0.30	0.40	0.009	0.012	0.016	
С	0.15	0.20	0.25	0.006	0.008	0.010	
D	,	3.30 BSC 0.130 BSC			;		
D1	2.95	3.05	3.15	0.116	0.120	0.124	
D2	1.98	2.11	2.24	0.078	0.083	0.088	
E	3.30 BSC			0.130 BSC			
E1	2.95	3.05	3.15	0.116	0.120	0.124	
E2	1.47	1.60	1.73	0.058	0.063	0.068	
E3	0.23	0.30	0.40	0.009	0.012	0.016	
е	0.65 BSC			0.026 BSC			
G	0.30	0.41	0.51	0.012	0.016	0.020	
K	0.65	0.80	0.95	0.026	0.032	0.037	
L	0.30	0.43	0.56	0.012	0.017	0.022	
L1	0.06	0.13	0.20	0.002	0.005	0.008	
M	1.40	1.50	1.60	0.055	0.059	0.063	
θ	0 °		12 °	0 °		12 °	



SOLDERING FOOTPRINT* ^{4X} −0.66 PACKAGE OUTLINE 3.60 0.75 0.57 2.30 0.47 2.37 3.46 DIMENSION: MILLIMETERS

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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